Sheet 1 (A) of 1 SUBSTITUTES ORM PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. SERIAL NO. PATENT AND TRADEMARK OFFICE SSIT-114 10/711,649 **APPLICANT** INFORMATION DISCLOSURE Kawamura et al. STATEMENT BY APPLICANT (Use several sheets if necessary) **FILING DATE GROUP** 09/29/2004 1756 **U.S. PATENT DOCUMENTS** ISSUE FILING DATE **EXAMINER** IF APPROPRIATE **PATENTEE CLASS SUBCLASS** PATENT NUMBER DATE INITIAL MNJ 6 5 9 6 lo 8 07/22/2003 DeYoung et al. 134 09/13/2001 A.A A.B A.C A.D A.E ٠. A.F A.G A.H A.I A.J A.K FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS **TRANSLATION COUNTRY OR PUBLICATION** DOCUMENT **SUBCLASS** (YES/NO) NUMBER DATE PATENT OFFICE **CLASS** MDIT **Abstract Only** JP H01L 21/68 10/09/1992 A.L JP 4-284648 H01L 21/68 **Abstract Only** J۶ 05/22/1987 JP 62-111442 A.M 3/08 JP **B23Q Abstract Only** 10/24/1988 A.N JP 63-256326 A.O A.P A.Q OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication) Cotte et al., Process and Apparatus for Contacting a Precision Surface with Liquid or Supercritical Carbon Dioxide. US A.R MDH 2003/0196679 A1; Publication Date 10/23/2003; Filing Date 04/18/2002; U.S. Class 134/1 A.S A.T **EXAMINER** DATE CONSIDERED

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A.S Los Alamos National Laboratory, Solid State Technology, pp. S10 & S14, October 1998.	
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		D.C	4	8	6	5	0	6	1	09/12/1989	Fowler et al.		134	108		07/22/1983
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		nitial If cit	atio	n co	nsi	dere	d, w	heth	ner or		mance. Draw line throug		-/	n conform	nance <u>an</u>	not considered.

Sheet 5 (E) of 28

SUBSTITUTE (MODIFIED)	FORM P	TO-	144	9						ENT OF COMMERCE RADEMARK OFFICE	ATTY. SSIT-1	DOCKET NO 14).	SERIA 10/711	
									OSURE LICANT		APPLI(Kawam	CANT nura et al.			
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MDH	E.A	4	9	4	4	8	3	7	07/31/1990	Nishikawa et al.	-	118	719		06/23/1989
	E.B	4	9	5	1	6	0	1	08/28/1990 10/02/1990	Maydan et al.		134	31		11/27/1985
	E.C	4	9	6	0	1	4	0			····	134	25.4		10/24/1989
	E.D	4	9	8	3	2	2	3	01/08/1991	Gessner		134	38		07/21/1988
	E.E	5	0	1	1	5	4	2	04/30/1991	Weil Jackson et al.		134	1		12/07/1988
	E.F	5	0	1	3	3	6	6		414	786		01/13/1988		
	E.G	5	0	4	4	8	7	1	09/03/1991	Davis et al.		417	46		08/11/1989
	E.H	5	0	6	2	7	7	0	11/05/1991	Story et al.		210	748		04/03/1989
	E.I	5	0	6	8	0	4	0	12/10/1991	Jackson et al		134	2		09/11/1990
- \	E.J	5	0	7	1	4	8	5	04/21/1992	Matthews et al.		34	12		08/09/1988
	E.K	5	1	0	5	5	5	6	J	Kurokawa et al. BLISHED FOREIGN PA	TENT A	L	1		1 0000
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	E.S	K. We	Jack	kso:	n et I, NJ	ai.,	<u>Surf</u> . 87	actar	nts and Micron Spring 1998.	nulsions in Supercritical	<u>Fluids,</u> S	upercritical F	fluid Clea	ning, No	yes Publications,
V	E.T	M. 19		szc	wski	, Pr	odu	ction	of Metal and S	Semiconductor Nanopar	licles in P	olymer Syst	ems, Poli	mery, pp	o. 65-73, February
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	9/4	7		<u>ソ</u>	<u> </u>		<u> </u>			mance. Draw line through		7		nance ar	nd not considered.
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Sheet 6 (F) of 28

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	DH	F.A	5	1	4	3	1	0	3	09/01/1992	Basso et al.		134	98.1		01/04/1991
	l	F.B	5	1	5	8	7	0	4	10/27/1992	Fulton et al.		252	309		07/25/1990
		F.C	5	1	6	7	7	1	6	12/01/1992	Boitnott et al.		118	719		09/28/1990
		F.D	5	1	6	9	2	9	6	12/08/1992	Wilden		417	395		03/10/1989
		F.E	5	1	6	9	4	0	8	12/08/1992	Biggerstaff et al.		29	25.01		01/26/1990
		F.F	5	1	7	4	9	1	7	12/29/1992	Monzyk		252	60		07/19/1991
		F.G	5	1	8	5	0	5	8	02/09/1993	Cathey, Jr.		156	656		01/29/1991
		F.H	5	1	8	5	2	9	6	02/09/1993	Morita et al.		437	229		04/24/1991
		F.I	5	1	8	6	5	9	4	02/16/1993	Toshima et at.₄		414	217		04/19/1990
		F.J	5	1	8	6	7	1	8	02/16/1993	Tepman et al.		29	25.01		04/15/1991
	1	F.K	5	1	8	8	5	1	5	02/23/1993	Horn		417	63		06/03/1991
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M	517	F.R	G. Wa	L. E	akk 'CO	er e , Mi	t al.	., <u>S</u> u	rface J Elec	Cleaning and trochem Soc.	Carbonaceous Film Re Vol. 145, No. 1, pp. 28	moval U: 4-291, Ja	sing High Pre Inuary 1998.	essure, H	gh Temp	perature Water, and
		F.S				et a			ging f	Polymers with	Supercritical Carbon Die	oxide, Ad	vanced Mate	rials, Vol.	9, No. 1	13, pp. 1039-1043,
	,	F,T	E.	M. I	Rus:	sick and	et a	ıt., <u>S</u> Ilutio	on Pr	critical Carbon evention, ACS	Dioxide Extraction of S Symposium Series, Vo	olvent fro I. 670, pp	m Micro-Mac . 255-269, O	chined St ctober 21	ructures.	, Supercritical Fluids
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									OSURE		APPLII Kawam	CANT nura et al.			
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MDIT	G.A	5	1	9	0	3	7	3	03/02/1993	Dickson et al.	•	366	146		12/24/1991
1	G.B	5	1	9	1	9	9	3	03/09/1993	Wanger et al.		220	333		02/24/1992
	G.C	5	1	9	3	5	6	0	03/16/1993	Tanaka et al.		134	56 R		06/24/1991
	G.D	5	1	9	5	8	7	8	03/23/1993	Sahlavo et al.		417	393		05/20/1991
	G.E	5	1	9	6	1	3	4	03/23/1993	Jackson		252	103		08/17/1992
	G.F	5	2	0	1	9	6	0	04/13/1993	Starov		134	11		02/26/1992
	G.G	5	2	1	3	4	8	5	05/25/1993	Wilden		417	393		11/19/1991
	G.H	5	2	1	3	6	1	9	05/25/1993	Jackson et al.		134	1		11/30/1989
	G.I	5	2	1	5	5	9	2	06/01/1993	Jackson		134	1		01/22/1991
	G.J	5	2	1	7	0	4	3	06/08/1993	Novakovi ⁴		137	460		02/24/1992
	G.K	5	2	2	1	0	1	9	06/22/1993	Pechacek et al.		220	315		11/07/1991
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MOIT	G.R	N. Flu	Dah iids	me - Ex	n et trac	al., tion	Sup	ercrit I Poll	ical Fluid Extrution Prevention	action of Grinding and M on, ACS Symposium Se	tetal Cutt ries, Vol.	ing Waste Co 670, pp. 270	ontamina)-279, Oc	ted with tober 21	Olls, Supercritical , 1997.
	G.S	C.	M. V	Val	, <u>Su</u> 7, 19	<u>serc</u> 97.	ritic	al Flu	id Extraction:	Metals as Complexes, J	lournal of	Chromatogr	aphy A, \	/ol. 785,	pp. 369-383,
1	G.T	C. Ne	Xu e	et ai	l., <u>S</u> e	ubm and	icro I Py	n-Siz rolysi	ed Spherical \ s, Appl. Phys.	/ttrium Oxide Based Pho Lett., Vol. 71, No. 22, p	osphors F p. 1643-1	Prepared by S 645, Septem	Supercriti nber 22, 1	cal CO ₂ - 1997.	<u>Assisted</u>
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Sheet 8 (H) of 28

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									OSURE LICANT		APPLIO Kawam	CANT nura et al.			
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MDt	H.A	5	2	2	2	5	7	6	06/29/1993	Budde Thompson et al.		134	155		07/30/1992
	H.B H.C	5	2	2	5	1	7	3	07/06/1993	Wai		423	2		10/25/1991
	H.D	5	2	3	6	6	0	2	08/17/1996	Jackson	_	210	748		01/28/1991
	H.E	5	2	3	6	6	6	9	08/17/1993	Simmons et al-		422	113		05/08/1992
-	H.F	5	2	3	7	8	2	4	08/24/1993	Pawliszyn		62	51.1		02/16/1990
	H.G	5	2	3	8	6	7	1	08/24/1993	Matson et al.		423	397		11/22/1988
	н.н	5	2	4	0	3	9	0	08/31/1993	Kvinge et al.		417	393		03/27/1992
-	H.3	5	2	4	3	8	2	1	09/14/1993	Schuck et al.		62	50.6	M	06/24/1991
 	H.J	5	2	4	6	5	0	0	09/21/1993	Samata et al.		118	719		09/01/1992
	н.к	5	2	5	0	0	7	8	10/05/1993	Saus et al.		8	475		05/12/1992
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	H.S	H.	Klei	n e	t al.,	Сус	oik	Organ	nic Carbonates	Serve as Solvents and	Reactive	Diluents, Co	oatings W	orld, pp	. 38-40, May 1997.
	н.т	J. I Vo	B0hl	er e	et al. o. 5,	, <u>Lir</u> pp.	139	Arra 11-13	y of Compleme 98, May 1997.	entary Metal Oxide Sem	iconduct	or Double-Pa	ss Metal	Micro-m	irrors, Opt. Eng.
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MNJ	I.A	5	2	5	1	7	7	6	10/12/1993	Morgan,	Jr. et al.		220	360		08/12/1991
1010	I.B	5	2	6	1	9	6	5	11/16/1993	Moslehi		J###**	134	1		08/28/1992
	I.C	5	2	6	6	2	0	5	113-1003	Fulton et	al.		210	639	_	07/01/1992
	I.D	5	2	6	7	4	5	5	12/07/1993	Dewees	et al.		68	5 C		07/13/1992
	I.E	5	2	6	9	8	1	5	12/14/1993	Schlenke	er et al.		8	475		11/13/1992
I.F 5 2 6 9 8 5 0 12/14/1993 Jackson												134	2		08/27/1990	
I.G 5 2 7 4 1 2 9 12/28/1993 Natale et al.														349		06/12/1991
1.G 5 2 7 4 1 2 9 12/26/1993 Natale et al. 1.H 5 2 8 0 6 9 3 01/25/1994 Heudecker														306		10/07/1992
	1.1	5	2	8	5	3	5	2	et al.		361	707		07/15/1992		
	1.J	5	2	8	8	3	3	3	02/22/1994	Tanaka e	et al.		134	31		07/29/1992
	I.K	5	2	9	0	3	6	1	03/01/1994	Hayashio	da et al.		134	2		01/23/1992
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İ	I.S	J. De	B. M	1cCi	ain (et al	., <u>D</u> 96.	esign	of Nonionic S	Surfactants	for Supercriti	cal Carbo	on Dioxide , S	Science, 1	Vol. 274,	pp. 2049-2052,
V	I.T	L.	Zna eatn	idi e	t al.	, <u>Ba</u> //q(0	tch OCH	and S	Semi-Continuo Naterials Rese	ous Synthes arch Bullet	sis of Magnes in, Vol. 31, N	sium Oxio o. 12, pp.	le Powders fi 1527-1535,	rom Hydr Decemb	olysis an er 1996.	d Supercritical
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MDH	J.A	5	2	9	4	2	6	1	03/15/1994	McDermott et al.		134	7		11/02/1992
	J.B	5	2	9	8	0	3	2	03/29/1994	Schlenker et al.		8	475		08/08/1992
	J.C	5	3	0	4	5	1	5	04/19/1994	Morita et al.		437	231		08/07/1992
	J.D	5	3	0	6	3	5	0	04/26/1994	Hoy et al.		134	22.14		04/27/1992
	J.E	5	3	1	2	8	8	2	05/17/1994	DeSimone et al.		526	201		07/30/1993
	J.F	5	3	1	3	9	6	5	05/24/1994	Palen		134	61		06/01/1992
	J.G	5	3	1	4	5	7	4	05/24/1994	Takahashi		156	646		06/25/1993
	J.H	5	3	1	6	5	9	1	05/31/1994	Chao et al.		134	34		08/10/1992
	J.1	5	3	2	0	7	4	2	06/14/1994	Fletcher et al.		208	89		10/19/1992
	J.J	5	3	2	8	7	2	2	07/12/1994	Ghanayem et al.		427	250		11/06/1992
	J.K	5	3	3	4	3	3	2	08/02/1994	Lee		252	548		07/09/1992
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mout	J.R				ros, er 19		thes	sis of	Titanium Diox	ide Particles in Supercri	tical CO,	, J. Supercrit	ical Fluid	s, Vol. 9,	, pp. 172-176,
	J.S	V. Ch	G. C	Cou	rteci	uisse /ol. :	e et 35, l	al., <u>K</u> No. 8	inetics of the pp. 2539-254	Titanium Isopropoxide D 15, August 1996.	ecompo:	sition In Supe	ercritical I	sopropyl	Al <u>ohol,</u> Ind. Eng.
V	J.T	A. Su	Gat	oor	et al	. BI	ock Deve	and f	Random Copo lent, SPIE, Vo	lymer Resists Designed I. 2724, pp. 410-417, Ju	for 193 i ne 1996.	nm Lithograp	hy and E	nvironme	entally Friendly
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K,		K.D	5	3	5	2	3	2	7	10/04/1994	Witowski		156	646		07/10/1992
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K.H 5 3 6 8 1 7 1 11/29/1994 Jackson 134 147 07/20/1992		K.F	5	3	5	6	5	3	8	10/18/1994	Wai et al.		210	634		10/21/1991
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		L.C	5	4	0	3	6	2	1	04/04/1995	Jackson et al.		427	255.1		10/01/1993
		L.D	5	4	0	3	6	6	5	04/04/1995	Alley et al.		428	447		06/18/1993
		L.E	5	4	0	4	8	9	4	04/11/1995	Shiraiwa		134	66		05/18/1993
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)		L.S	E. 3, ₁	F. G	iloy 182	na e -192	t al.	, <u>Su</u> gus	percr	itical Water O	xidation Research and D	Developm	ent Update,	Environm	ental Pr	ogress, Vol. 14, No.
V	L.S E. F. Gloyna et al., <u>Supercritical Water Oxidation Research and Development Update</u> , Environmental Progress, Vol. 14, No. 3, pp. 182-192, August 1995. L.T P. Gallagher-Wetmore et al., <u>Supercritical Fluid Processing: A New Dry Technique for Photoresist Developing</u> , SPIE, Vol. 2438, pp. 694-708, June 1995.															
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	M.D	5	4	9	4	5	2	6	02/27/1996	Paranjp	e		134	1		05/04/1995
	M.E	5	5	0	0	0	В	1	03/19/1996	Bergma	n		156	646.1		12/05/1994
	M.F	5	5	0	1	7	6	1	03/26/1996	Evans e	et al.		156	344		10/18/1994
	M.G	5	5	0	3	1	7	6	04/02/1996	Dummir	e et al.		137	15		10/25/1994
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1	M.T	R.	D. /	Allei	ı et	al.,	Perf	orma	nce Properties	s of Near-	Monodisperse	Novolak	Resins, SPII	E, Vol. 24	38, pp. 2	250-260, June 1995.
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	N.D	5	5	5	0	2	1	1	08/27/1996	DeCrosta et al.		528	489		12/17/1992
	N.E	5	5	7	1	3	3	0	11/05/1996	Kyogoku		118	719		11/12/1993
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	P.D	5	6	8	3	9	7	7	11/04/1997	Jureller et al.		510	286		03/06/1995
	P.E	5	6	8	8	8	7	9	11/18/1997	DeSimone		526	89		02/07/1997
	P.F	5	7	0	0	3	7	9	12/23/1997	Biebl		216	2		02/14/1996
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	P.I	5	7	1	4	2	9	9	02/03/1998	Combes et al.		430	137		11/04/1996
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	Q.E	5	7	6	6	3	6	7	06/16/1998	Smith et al.		134	2		05/14/1996
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		R.C	5	8	4	7	4	4	3	12/08/1998	Cho et al.		257	632		11/14/1996
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S.R Kawakami et al., A Super Low-k(k=1,1) Silica Aerogel Film Using Supercritical Drying Technique, IEEE, pp. 143-145, 2000.

S.S R. F. Reidy, Effects of Supercritical Processing on Ultra Low-k Films, Texas Advanced Technology Program, Texas Instruments and the Texas Academy of Mathematics and Science

S.T Anthony Muscat, Backend Processing Using Supercritical CO₂, University of Arizona

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m	DIA	V.A	6	0	6	3	7	1	4	05/16/2000	Smith et al.		438	778		11/14/1996
-	 	V.B	6	0	6	7	7	2	8	05/30/2000	Farmer et al.		34	470		02/13/1998
		V.C	6	0	7	7	0	5	3	06/20/2000	Fujikawa et al.		417	399		04/10/1998
		V.D	6	0	7	7	3	2	1	06/20/2000	Adachi et al.		29	25.01		11/07/1997
-		V.E	6	0	8	2	1	5	0	07/04/2000	Stucker		68	18 R		07/30/1999
		V.F	6	0	8	5	9	3	5	07/11/2000	Malchow et al.		220	813		08/10/1998
		V.G	6	0	9	7	0	1	5	08/01/2000	McCullough et al.	•	219	686	-	10/14/1998
		V.H	6	0	9	9	6	1	9	08/08/2000	Lansbarkis et al.		95	118		10/13/1998
		V.I	6	1	0	0	1	9	8	08/08/2000	Grieger et al.		438	692		02/27/1998
		V.J	6	1	1	0	2	3	2	08/29/2000	Chen et al.		29	25.01		10/01/1998
一、	1	V.K	6	1	1	4	0	4	4	09/05/2000	Houston et al.,		428	447		05/30/1997
	<u> </u>		•			FC	RE	IGN	PAT	ENTS OR PU	BLISHED FOREIGN PA	TENT A	PPLICATION	ıs		
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		v.s	Bit	erg dule	er e e, U	t al.	, <u>M∈</u> 202/	tho 000	d of C 1929	Depositing Met A1, Publication	al Film and Metal Depos in Date 01/03/2002, File	ition Clus d 04/24/2	ster Tool Incl 1001, U.S. Cl	uding Su ass 438/	percritica 584.	al Drying/Cleaning
	/	V.T	De 08	You /22/	ing 200	et al	., M	etho 09/	ods fo	or Removing P 01, U.S. Class	articles from Microelectr 134/36	onic Stru	ictures, US 2	002/0112	746 A1,	Publication Date
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•									OSURE LICANT	•	APPLI(Kawam	CANT nura et al.			
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MDI	y W.A	6	1	2	2	5	6	6	09/19/2000	Nguyen et al.		700	218		03/03/1998
	W.B	6	1	2	8	8	3	0	10/10/2000	Bettcher et al.		34	404	,	05/15/1999
	w.c	6	1	4	0	2	5	2	10/31/2000	Cho et al.		438	781		05/05/1998
	W.D	6	1	4	5	5	1	9	11/14/2000	Konishi et al.		134	95.2		05/15/1997
	W.E	6	1	4	9	8	2	8	11/21/2000	Vaartstra		216	57		05/05/1997
	W.F	6	1	5	9	2	9	5	12/12/2000	Maskara et al.		118	688		04/22/1999
	W.G	6	1	6	4	2	9	7	12/26/2000	Kamikawa		134	61		06/12/1998
	W.H	6	1	7	1	6	4	5	01/09/2001	Smith et al.		427	96		07/15/1998
	W.I	6	1	8	6	7	2	2	02/13/2001	Shiral		414	217		02/24/1998
	W.J	6	2	6	0	9	4	3	03/13/2001	Romack et al.		510	285		,05/27/1999
	W.K	6	+	10	3	5	8	2	03/20/2001	Berner et al.		29	25.01		07/15/1996
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)TH	ER	DOC	UMENTS (Ind	uding Author, Title, Date	e, Place o	of Publication)		
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	w.s	CP	hiou, ublic	, Mo	ethod	of ite 1	Rins	ing F 3/200	Residual Etchio 12, Filed 03/29	ng Reactants/Products of /2001, U.S. Class 438/6	on a Sem 89	iconductor V	<u>/afer</u> , US	2002/01	142595 A1,
1	W.T	M	asuc	da e	t al.,	Pro	ces 1/0	s and	Apparatus fo	r Removing Residues fr /2002, U.S. Class 438/6	om the M	licrostructure	of an Ob	<u>ject,</u> US	2002/0164873 A1,
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•	,								OSURE LICANT	•	APPLII Kawan	CANT nura et al.			
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MDH	X.A	6	2	1	6	3	6	4	04/17/2001	Tanaka et al. *		34	448		04/14/1999
	X.B	6	2	2	4	7	7	4	05/01/2001	DeSimone et al.		210	634		02/12/1999
	x.c	6	2	2	8	5	6	3	05/08/2001	Starov et al.		430	327		09/17/1999
	X.D	6	2	2	8	8	2	6	05/08/2001	DeYoung et al.		510	291		10/18/1999
	X.E	6	2	3	2	2	3	8	05/15/2001	Chang et al.		438	725		02/08/1999
	X.F	6	2	3	2	4	1	7	05/15/2001	Rhodes et al.		526	171		09/12/1997
X.G 6 2 3 5 6 3 4 05/22/2001 White et al.															05/20/1998
X.H 6 2 3 9 0 3 8 05/29/2001 Wen 438 745 09/09/1996 X.I 6 2 4 1 8 2 5 06/05/2001 Wytman 118 733 04/16/1999															09/09/1996
X.H 6 2 3 9 0 3 8 05/29/2001 Wen 438 745 09/05 X.I 6 2 4 1 8 2 5 06/05/2001 Wytman 118 733 04/16															04/16/1999
X.H 6 2 3 9 0 3 8 05/29/2001 Wen 438 X.I 6 2 4 1 8 2 5 06/05/2001 Wytman 118 X.J 6 2 4 2 1 6 5 06/05/2001 Vaartstra 430															08/28/1998
1	х.к	6	2	4	4	1	2	1	06/12/2001	Hunter		73	865.9		03/06/1998
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1	X.T Reid et al., Method for Removing a Sacrificial Material with a Compressed Fluid, US 2003/0047533 A1, Publication Date 03/13/2003, Filed 06/10/2002, U.S. Class 216/24 Compressed Fluid														
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MDH	Y.A	6	2	5	1	2	5	0	06/26/2001	Keigler .		205	89		09/03/1999
	Y.B	6	2	5	5	7	3	2	07/03/2001	Yokoyama et al.		257	760		08/03/1999
	Y.C	6	2	7	0	5	3	1	08/07/2001	DeYoung et al.		8	142		08/28/1998
	Y.D	5	2	7	0	9	4	8	08/07/2001	Sato et al.		430	314		06/07/1999
	Y.E	6	2	7	7	7	5	3	08/21/2001	Mullee et al.		438	692		09/28/1999
	Y.F	6	2	8	4	5	5	8	09/04/2001	Sakamoto		438	30		11/25/1998
	Y.G	6	2	8	6	2	3	1	09/11/2001	Bergman et ale		34	410		01/12/2000
	Y.H	6	3	0	5	6	7	7	10/23/2001	Lenz		269	13		03/30/1999
	Y.I	6	3	6	6		430	329		05/27/1998					
	Y.J 6 3 0 6 5 6 4 10/23/2001 Mullee 430 Y.J 6 3 1 9 8 5 8 11/20/2001 Lee et al. 430														07/11/2000
	Y.K	6	3	3	1	4	8	7	12/18/2001	Koch		438	692		02/27/2001
				. <u></u>	FC	RE	IGN	PAT	ENTS OR PU	BLISHED FOREIGN PA	TENT A	PPLICATION	IS		
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	Y.S	Xu	et a	al., <u>S</u>	Supe 5/20	ercri 02,	tical U.S	Fluid . Clas	1 Cleaning of S ss 510/175	Semiconductor Substrate	es, US 2	003/0125225	A1, Publ	ication C	Date 07/03/2003,
1	Y.T	Ja Pt	ckso	on, [Den:	e F	luid 1/0	Clea 6/200	ning Centrifug 3, Filed 03/13	al Phase Shifting Separ /2001, U.S. Class 210/8	ation Pro 6.	cess and Ap	paratus, l	JS 2003	/0205510 A1,
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mI		Z.A	6	3	3	4	2	6	6	01/01/2002	Moritz et al.			34	337		09/20/2000
1	•	Z.B	6	3	4	4	1	7	4	02/05/2002	Miller et al.			422	98		04/12/1999
<u> </u>		Z.C	6	3	4	4	2	4	3	02/05/2002	McClain et al	1.		427	388.1		08/02/2001
		Z.D	6	3	5	5	0	7	2	03/12/2002	Racette et al	l.		8	142		10/15/1999
		Z.E	6	3	5	8	6	7	3	03/19/2002	Namatsu			430	311		09/03/1999
		Z.F	6	3	6	1	6	9	6	03/26/2002	Spiegelman	et al.		210	662		01/19/2000
		Z.G	6	3	6	7	4	9	1	04/09/2002	Marshall et a	al.		134	104.4		09/15/2000
	Z.H 6 3 8 0 1 0 5 04/30/2022 Smith et al. 438														778		06/02/1999
	Z.I 6 3 8 8 3 1 7 05/14/2002 Reese 257														713		09/25/2000
	 	Z.J	6	3	8	9	6	7	7	05/21/2002	Lenz			29	559		08/30/2001
	\downarrow	Z.K	6	4	1	8	9	5	6	07/16/2002	Bloom			137	14		11/15/2000
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		z.s	De 20	You 04/0	ng 1020	et al)518	., <u>M</u>	etho Pu	ods fo	or Transferring tion Date 02/0	Supercritical F 5/2004, Filed 0	Fluids in M 5/30/2003	licroelect 3, U.S. Cl	ronic and Ot ass 134/30.	her Indus	trial Pro	cesses, US
	,	Z.T	Ko	rzer	ski atio	et a	I., <u>S</u>	upe 5/0	rcritic	cal Carbon Did 14, Filed 10/31	oxlde/Chemical /2002, U.S. Cla	Formulat ass 510/1	ion for R	emoval of Ph	otoresist	<u>s,</u> US 20	04/0087457 A1,
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	NT	AA.A	6	4	2	5	9	5	6	07/30/2002	Cotte et al.		134	3		01/05/2001
1	<u>/</u>	AA.B	6	4	3	6	8	2	4	08/20/2002	Chooi et al.		438	687		07/02/1999
		AA.C	6	4	5	1	5	1	0	09/17/2002	Messick et al.		430	311		02/21/2001
		AA.D	6	4	5	4	5	1	9	09/24/2002	Toshima et al.		414	805		03/07/1997
		AA.E	6	4	5	4	9	4	5	09/24/2002	Weigl et al.		210	634		11/01/2000
		AA.F	6	4	5	4	9	4	5	09/24/2002	Weigl et al.		210	634		11/01/2000
AA.G 6 4 5 8 4 9 4 10/01/2002 Song et al.													430	5		04/27/2000
AA.H 6 4 6 1 9 6 7 10/08/2002 Wu et al.														705		07/16/2002
AA.H 6 4 6 1 9 6 7 10/08/2002 Wu et al. 438 705 AA.I 6 4 6 4 7 9 0 10/15/2002 Sherstinsky et al. 118 715															03/17/2000	
		AA.J	6	4	7	2	3	3	4	10/29/2002	Ikakura et al.		438	778		04/03/2001
	/	AA.K	6	4	7	9	4	0	7	11/12/2002	Yokoyama et al.		438	788		01/23/2001
	¥	L	L	<u> </u>	J	FC	DRE	IGN	PAT	ENTS OR PU	BLISHED FOREIGN PA	TENT A	PPLICATION	S		
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		AA.Q														
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MDIT	BB.A	6	5	5	4	5	0	7	04/29/2003	Namatsu ,		396	611		12/20/2001
1	BB.B	6	5	5	8	4	7	5	05/06/2003	Jur et al.		134	21		04/10/2000
	BB.C	6	5	6	1	2	1	3	05/13/2003	Wang et al.		137	263		06/05/2001
	BB.D	6	5	6	1	2	2	0	05/13/2003	McCullough et al.		137	565.12		04/23/2001
	BB.E	6	5	6	1	4	8	1	05/13/2003	Filonczuk		251	129.12		08/13/2001
	BB.F	6	5	6	1	7	6	7	05/13/2003	Berger et al.		417	53		08/01/2001
	BB.G	6	5	6	2	1	4	6	05/13/2003	DeYoung et al.		134	30	•	08/17/2001
	BB.H	6	5	6	4	8	2	6	05/20/2003	Shen		137	505.18		07/24/2001
	BB.I	6	5	7	6	1	3	8	06/10/2003	Sateria et al.		210	664		12/14/2000
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Include a copy of this form with next communication to Applicant.

Sheet 2 (B) of 14

SUBSTITUTE (MODIFIED)	FORM	-TO-	1449	9						COMMERCE MARK OFFICE	ATTY SSIT-	. DOCKET N 114	0.	SERI/ 10/71	AL NO. 1,649
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Sheet 3 (C) of 14

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Sheet 4 (D) of 14

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Sheet 5 (E) of 14

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Sheet 6 (F) of 14

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Sheet 7 (G) of 14 ATTY. DOCKET NO. SERIAL NO. SUBSTITUTE FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE 10/711,649 PATENT AND TRADEMARK OFFICE (MODIFIED) **SSIT-114** APPLICANT INFORMATION DISCLOSURE STATEMENT BY APPLICANT Kawamura et al. **GROUP** FILING DATE (Use several sheets if necessary) September 29, 2004 1756 (37 CFR 1.98(b)) **U.S. PATENT DOCUMENTS** FILING DATE **EXAMINER** ISSUE IF APPROPRIATE **SUBCLASS** INITIAL PATENT NUMBER DATE **PATENTEE CLASS** G.A G.B G.C G.D G.E G.F G.G G.H ú G.I G.J G.K FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS **PUBLICATION COUNTRY OR TRANSLATION** DOCUMENT PATENT OFFICE CLASS **SUBCLASS** (YES/NO) DATE NUMBER HO1L 21/302 **Abstract Only** 08/21/1990 Japan G.L JP 2-209729 **Abstract Only** 21/56 12/18/1990 Japan HO1L G.M JP 2-304941 021/027 **Abstract Only** H01L G.N JP 7-142333 06/02/1995 Japan **Abstract Only** H01L 21/56 07/16/1996 JP 8-186140 A Japan G.O H01L 021/027 **Abstract Only** G.P JP 8-222508 A 08/30/1996 Japan 21/68 H01L **Abstract Only** G.Q JP 10-144757 A 05/29/1998 Japan OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication) G.R G.S

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Sheet 8 (H) of 14

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Sheet 9 (I) of 14

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Sheet 10 (J) of 14 SERIAL NO. ATTY, DOCKET NO. SUBSTITUTE FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE **SSIT-114** 10/711,649 (MODIFIED) APPLICANT INFORMATION DISCLOSURE Kawamura et al. STATEMENT BY APPLICANT **GROUP** (Use several sheets if necessary) FILING DATE September 29, 2004 1756 (37 CFR 1.98(b)) **U.S. PATENT DOCUMENTS** FILING DATE ISSUE EXAMINER IF APPROPRIATE **PATENTEE** CLASS SUBCLASS PATENT NUMBER DATE INITIAL J.A J.B J.C J.D J.E J.F J.G J.H J.I J.J J.K FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS **TRANSLATION COUNTRY OR PUBLICATION** DOCUMENT SUBCLASS (YES/NO) **CLASS** PATENT OFFICE NUMBER DATE MNT C23C 16/00 PCT 12/03/1987 J.L WO 87/07309 B08B 7/00 **PCT** 06/14/1990 WO 90/06189 J.M 3/00 **Abstract Only** C22B **PCT** 11/15/1990 WO 90/13675 J.N 21/00 H01L J.O WO 91/12629 A 08/22/1991 **PCT** Abstract Only PCT D06B 5/16 07/22/1993 WO 93/14255 J.P 11/76 Abstract Only 07/22/1993 **PCT D06M** WO 93/14259 J.Q OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication) J.R J.S

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Sheet 11 (K) of 14

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Sheet 12 (L) of 14 ATTY, DOCKET NO. SERIAL NO. **SUBSTITUTE FORM PTO-1449** U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE SSIT-114 10/711,649 (MODIFIED) INFORMATION DISCLOSURE **APPLICANT** Kawamura et al. STATEMENT BY APPLICANT **GROUP** (Use several sheets if necessary) FILING DATE September 29, 2004 1756 (37 CFR 1.98(b)) U.S. PATENT DOCUMENTS FILING DATE ISSUE **EXAMINER** IF APPROPRIATE PATENTEE **CLASS SUBCLASS** PATENT NUMBER DATE INITIAL L.A L.B L.C L.D L.E L.F L.G L.H L.I L.K FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS **TRANSLATION COUNTRY OR PUBLICATION** DOCUMENT (YES/NO) **SUBCLASS** PATENT OFFICE CLASS NUMBER DATE MAN B65D 55/00 PCT 02/15/2001 L.L WO 01/10733 A1 H01L 21/00 05/10/2001 PCT WO 01/33613 A2 L.M H01L 21/00 WO 01/33615 A3 05/10/2001 PCT L.N 51/02 F16K L.O WO 01/55628 A1 08/02/2001 PCT 09/20/2001 PCT B08B 7/00 WO 01/68279 A2 L.P B24C 1/00 10/11/2001 **PCT** WO 01/74538 A1 L.Q OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication) L.R L.S DATE CONSIDERED

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Sheet 14 (N) of 14 U.S. DEPARTMENT OF COMMERCE ATTY, DOCKET NO. SERIAL NO. **SUBSTITUTE FORM PTO-1449** 10/711,649 PATENT AND TRADEMARK OFFICE (MODIFIED) **SSIT-114 APPLICANT** INFORMATION DISCLOSURE STATEMENT BY APPLICANT Kawamura et al. **GROUP** FILING DATE (Use several sheets if necessary) September 29, 2004 1756 (37 CFR 1.98(b)) U.S. PATENT DOCUMENTS FILING DATE ISSUE **EXAMINER** IF APPROPRIATE **SUBCLASS CLASS** PATENT NUMBER DATE PATENTEE INITIAL N.A N.B N.C N.D N.E N.F N.G N.H N.I N.J N.K FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS TRANSLATION **PUBLICATION COUNTRY OR** DOCUMENT (YES/NO) PATENT OFFICE **CLASS SUBCLASS** DATE NUMBER PCT H01L MDH 10/04/2003 WO 03/030219 A2 N.L N.M N.N N.O . . N.P N.Q OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication) N.R

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ELECTRONIC INFORMATION DISĆLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention

A METHOD FOR SUPERCRITICAL CARBON DIOXIDE PROCESSING OF FLUORO-CARBON FILMS

Application Number:

10/711649

Confirmation Number:

5648

First Named Applicant:

Kohei Kawamura

Attorney Docket Number:

SSIT-114

Art Unit:

1756

Examiner:

Search string:

(6485895 or 6486078 or 6492090 or 6500605 or 6508259 or 6509136 or 6521466 or 6537916 or 6541278 or 6546946 or 6550484 or 6635582 or 6641678 or 6656666 or 6669916 or 6673521 or 6677244 or 6685903 or 6737725 or 6764552 or 6777312

or 6780765).pn

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	nit Cite.No. Patent No		Date	Patentee	Kind	Class	Subclass
MULT	1	6485895	2002-11-26	Choi et al.	B1	430	330
	2	6486078	2002-11-26	Rangarajan et al.	B1	438	778
	3	6492090	2002-12-10	Nishi et al.	B2	430	270.1
	4	6500605	2002-12-31	Mullee et al.	B1	430	329
	5	6508259	2003-01-21	Tseronis et al.	B1	134	105
	6	6509136	2003-01-21	Goldfarb et al.	B1	430	272.1
H	7	6521466	2003-02-18	Castrucci	B1	438	5
	8	6537916	2003-03-25	Mullee et al.	B2	438	692
	9	6541278	2003-04-01	Morita et al.	B2	438	3
	10	6546946	2003-04-15	Dunmire	B2	137	15.18
	11	6550484	2003-04-22	Gopjnath et al.	B1	134	1.2
	12	6635582	2003-10-21	Yun et al.	B2	438	745
	13	6641678	2003-11-04	DeYoung et al.	B2	134	36
	14	6656666	2003-12-02	Simons et al.	B2	430	322
	15	6669916	2003-12-30	Heim et al.	B2	423	245.1
	16	6673521	2004-01-06	Moreau et al.	B2	430	315
	17	6677244	2004-01-13	Ono et al.	B2	438	706
	18	6685903	2004-02-03	Wong et al.	B2	423	262
	19	6737725	2004-05-18	Grill et al.	B2	257	522
H	20	6764552	2004-07-20	Joyce et al.	B1	134	3
	21	6777312	2004-08-17	Yang et al.	B2	438	464

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Remarks

Note: Remarks are not for responding to an office action.

In accordance with the duty of candor and good faith imposed by 37 CFR 1.56 and means of complying therewith according to 37 CFR 1.97 and 1.98, the references listed in this Supplemental Information Disclosure Statement are called to the attention of the United States Patent and Trademark Office in connection with the above-identified patent application. No admission is made that the cited art represents the prior art or that the cited art is the most material art. In accordance with 37 CFR 1.97(b), this Supplemental Information Disclosure Statement shall be considered because it is filed before the mailing date of a first Office Action on the merits. The Examiner is urged to consider all the cited references and to make an independent decision with respect to their materiality. Applicants believe no fee is due in connection with the filing of this paper. If any additional fees are necessary to complete this communication, please apply them to Deposit Account No. 23-3000.

Signature

Examiner Name	Date
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